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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.		
10/763,508	01/23/2004	Christian Velez	FRG-15267	7237		
40854 7:	590 08/22/2005		EXAM	EXAMINER		
RANKIN, HI 4080 ERIE STI	LL, PORTER & CLA	LOUIE, W	LOUIE, WAI SING			
WILLOUGHBY, OH 44094-7836			ART UNIT	PAPER NUMBER		
			2814			
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Please find below and/or attached an Office communication concerning this application or proceeding.

				H.B			
-		Application No.	Applicant(s)				
Office Action Summary		10/763,508	VELEZ ET AL.				
		Examiner	Art Unit				
		Wai-Sing Louie	2814				
Period fo	The MAILING DATE of this communication or Reply	n appears on the cover sheet	vith the correspondence address -				
THE - External control	ORTENED STATUTORY PERIOD FOR R MAILING DATE OF THIS COMMUNICATI resions of time may be available under the provisions of 37 C SIX (6) MONTHS from the mailing date of this communication period for reply specified above is less than thirty (30) days, period for reply is specified above, the maximum statutory pure to reply within the set or extended period for reply will, by reply received by the Office later than three months after the led patent term adjustment. See 37 CFR 1.704(b).	ON. FR 1.136(a). In no event, however, may and the statutory minimum of the statute, cause the application to become	a reply be timely filed hirty (30) days will be considered timely. DNTHS from the mailing date of this communica ABANDONED (35 U.S.C. § 133).	ation.			
Status							
1)⊠	Responsive to communication(s) filed on	31 May 2005.					
2a)⊠	This action is FINAL. 2b)	This action is non-final.					
3)							
Disposit	ion of Claims						
5)□ 6)⊠ 7)□	Claim(s) 1-15,17,19 and 20 is/are pending 4a) Of the above claim(s) is/are wit Claim(s) is/are allowed. Claim(s) 1-15,17,19 and 20 is/are rejected Claim(s) is/are objected to. Claim(s) are subject to restriction a	hdrawn from consideration.					
Applicat	ion Papers						
10)	The specification is objected to by the Example The drawing(s) filed on is/are: a) Applicant may not request that any objection to Replacement drawing sheet(s) including the compact that the oath or declaration is objected to by the	accepted or b) objected to the drawing(s) be held in abey orrection is required if the drawir	ance. See 37 CFR 1.85(a). ng(s) is objected to. See 37 CFR 1.12				
Priority	under 35 U.S.C. § 119						
12) [a)	Acknowledgment is made of a claim for fo All b) Some * c) None of: 1. Certified copies of the priority docur 2. Certified copies of the priority docur 3. Copies of the certified copies of the application from the International B See the attached detailed Office action for	ments have been received. ments have been received in priority documents have bee ureau (PCT Rule 17.2(a)).	Application No en received in this National Stage				
2) Notice 3) Information	nt(s) ce of References Cited (PTO-892) ce of Draftsperson's Patent Drawing Review (PTO-94 rmation Disclosure Statement(s) (PTO-1449 or PTO/S er No(s)/Mail Date <u>7/04</u> .	8) Paper N	v Summary (PTO-413) o(s)/Mail Date f Informal Patent Application (PTO-152) 				

DETAILED ACTION

Claim Rejections - 35 USC § 112

The following is a quotation of the first paragraph of 35 U.S.C. 112:

The specification shall contain a written description of the invention, and of the manner and process of making and using it, in such full, clear, concise, and exact terms as to enable any person skilled in the art to which it pertains, or with which it is most nearly connected, to make and use the same and shall set forth the best mode contemplated by the inventor of carrying out his invention.

Claims 19 and 20 are rejected under 35 U.S.C. 112, first paragraph, as failing to comply with the written description requirement. The claim(s) contains subject matter which was not described in the specification in such a way as to reasonably convey to one skilled in the relevant art that the inventor(s), at the time the application was filed, had possession of the claimed invention.

- The disclosed specification does not disclose "the second contact forming a
 permanent electrical contact between a P-layer and an N-layer of the pn junction
 in the absorber region".
- The disclosed specification does not disclose, "the second contact includes a wire contact between a layer having the electrical potential of the p-layer and a layer having the electrical potential of the n-layer".

Claim Rejections - 35 USC § 103

The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

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(a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.

Claims 1-3, 5-15, 17, and 19-20 are rejected under 35 U.S.C. 103(a) as being unpatentable over Fouquet (US 5,252,839).

With regard to claims 1-2 and 9, Fouquet discloses a superluminescent light-emitting diode (col. 4, line 39 to col. 9, line 68 and fig. 2) comprising:

- A pn junction 56 and 58 (col. 6, lines 10-18 and fig. 2);
- A waveguide 40 and 42 defining an optical beam path (col. 5, line 66 to col. 6, line 3 and fig. 2);
- A heterostructure including a gain region 50 and an absorber region 52 in series with the gain region 50 in the optical beam path (col. 6, lines 7-10);
- The waveguide comprises two end facets, the end facets being perpendicular to the optical beam path (col. 6, lines 25-30 and fig. 2);
- A first contact for applying a voltage to the pn junction in its forward direction in the gain region (fig. 5), so as to produce light emission from the gain region 50 and along the optical beam path (col. 6, lines 25-28);
- A second contact contacting the pn junction in the absorber region 52 (fig. 5) and operable to remove charge carriers generated by absorption in the absorber region 52 at zero bias (col. 6, lines 12-18 and col. 8, line 28).

Fouquet discloses the second contact is split from the n-contact (col. 6, lines 36-40), but not being connected to an active voltage source. However, when the structure recited in the reference is substantially identical to that of the claims,

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claimed properties or functions are presumed to be obvious. Where the claimed and the prior art products are identical or substantially identical in structure or composition, or are produced by identical or substantially identical processes, a *prima facie* case of either anticipation or obviousness has been established. *In re Best*, 195 USPQ 430, 433 (CCPA 1977).

With regard to claim 3, Fouquet discloses the pn junction comprises an n-doped side 42 and where at least of the n-doped side 42 and the p-doped side 40 is connected, by the second contact, to a metallic surface 56 outside the heterostructure (fig. 2b).

With regard to claims 5 and 8, Fouquet discloses the semiconductor heterostructure in the gain region 50 comprises:

- A multiple quantum well (MQW) structure 32 (col. 5, lines 55-62) where the pn junction is formed in the MQW structure (fig. 2);
- A first n-doped cladding layer 42 being in electrical contact to a first metal electrode 54 and a second p-doped cladding layer 40 being in electrical contact to a second metal electrode 58 (fig. 2);
- The first and second electrodes 54 and 58 being interrupted between the gain region 50 and absorber region 52 (fig. 2).

With regard to claims 6-7, Fouquet discloses waveguide layers 40 and 42 (col. 5, lines 67-68) and the waveguide is index guided and gain guided (col. 3, lines 44-50).

With regard to claims 10 and 13, Fouquet discloses the semiconductor heterostructure forming a waveguide structure (layers 40, 32, and 42) defining an optical beam path (col. 5, line 67 to col. 6, line 3 and fig. 2) and including a gain region, the gain region emitting, upon

injection of a current through contact means 54 to 58, electromagnetic radiation into the optical beam path, the waveguide structure further including an forward bias (unbiased) pn junction in series with the gain region in the optical beam path (col. 6, lines 7-16 and fig. 2).

With regard to claims 11 and 15, Fouquet discloses the waveguide structure comprises two end facets 60 and 64 limiting the waveguide structure in a longitudinal direction parallel to the optical beam path, the end facets 60 and 64 being perpendicular to the longitudinal direction (col. 6, lines 24-48 and fig. 2).

With regard to claim 12, Fouquet discloses the SLED comprising monitoring means for monitoring a photocurrent (75 mA) generated by radiation emitted in the active region and absorbed in the unbiased pn junction, producing a monitoring signal (75 to 85 dB) being measure of the light emitted in the gain region 50 (col. 8, lines 14-35).

With regard to claim 14, Fouquet discloses the charge carrier reservoir comprises a metallic surface (fig. 2b).

With regard to claim 17, in addition to the limitations disclosed in claim 1 above, Fouquet also discloses:

• Two end facets 60 and 64 limiting the waveguide structure in a longitudinal direction parallel to the optical beam path, the end facets 60 and 64 being perpendicular to the longitudinal direction (col. 6, lines 24-48 and fig. 2).

With regard to claim 19, in addition to the limitations disclosed in claim 1 above, Fouquet also discloses:

• The second contact contacting the pn junction in the absorber region, the second contact forming a permanent electrical contact between a p-layer 56 and an n-layer 44 of the pn junction in the absorber region (fig. 2a and 2b).

With regard to claim 20, Fouquet discloses a wire contact between a layer 56 having the electrical potential of the p-layer and a layer 44 having the electrical potential of the n-layer (col. 6, lines 12-18).

Claim 4 is rejected under 35 U.S.C. 103(a) as being unpatentable over Fouquet (US 5,252,839) in view of Swirhun et al. (US 5,577,064).

With regard to claim 4, Fouquet discloses the pn junction in the gain region 50 and in the absorber region 52 is made of bulk semiconductor material (col. 9, line 10) comprising a p-doped component 40 and n-doped component 42, but do not disclose having a layer thickness exceeding 10 nm. However, Swirhun et al. disclose the thickness of the layers reflecting the light emitted from the action region are sized by a general formula λ 4n, where λ is the wavelength of the light emitted (Swirhun col. 2, lines 29-35). Swirhun et al. teach the SLED design is similar to the VCSEL except the absence of the mirrors and the layer is sized for reduced reflectance (Swirhun col. 2, lines 1-7). Fouquet and Swirhun et al. have substantially the same environment of the SLED. Therefore, it would have been obvious for the one with ordinary skill in the art to modify Fouquet's device with the teaching of Swirhun et al. to size the layer with the formula λ 4n in order to reduce reflectance for the device.

Fouquet discloses the wavelength emitted is 1.3 and 1.55 microns and, thus, the thickness of the layer sized by the formula λ 4n would exceed 10 nm.

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Response to Arguments

Applicant's arguments filed 5/31/05 have been fully considered but they are not

persuasive.

• Applicant argues that the second contact of Fouquet's device is connected to an

active voltage source. Please see the new rejection above.

Applicant argues Fouquet fails to disclose an unbiased pn junction of the

superluminescent light-emitting diode. However, Fouquet discloses the device

could be operated under no-bias condition (see fig. 1a).

• Applicant argues Fouquet does not disclose a charge reservoir in the device.

However, the charge reservoir is the bottom electrode (see page 7 of the

specification) and Fouquet discloses a bottom electrode in the device. Therefore,

statements of intended use, or functional language do not structurally distinguish

claims over prior art, which can function in the same manner, be labeled in the

same manner, or be used in the same manner. See in re Pearson, Ex parte Minks,

and In re Swinehart.

Conclusion

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Applicant's amendment necessitated the new ground(s) of rejection presented in this Office action. Accordingly, **THIS ACTION IS MADE FINAL**. See MPEP § 706.07(a). Applicant is reminded of the extension of time policy as set forth in 37 CFR 1.136(a).

A shortened statutory period for reply to this final action is set to expire THREE MONTHS from the mailing date of this action. In the event a first reply is filed within TWO MONTHS of the mailing date of this final action and the advisory action is not mailed until after the end of the THREE-MONTH shortened statutory period, then the shortened statutory period will expire on the date the advisory action is mailed, and any extension fee pursuant to 37 CFR 1.136(a) will be calculated from the mailing date of the advisory action. In no event, however, will the statutory period for reply expire later than SIX MONTHS from the date of this final action.

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Wai-Sing Louie whose telephone number is (571) 272-1709. The examiner can normally be reached on 7:30 AM to 4:00 PM.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Wael Fahmy can be reached on (571) 272-1705. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

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Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

Wsl

August 16, 2005.

PRIMARY EXAMINER